

Electronic Patent Application Fee Transmittal

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|---|--|-----------------|---------------|-----------------------------|
| Application Number: | 10773524 | | | |
| Filing Date: | 06-Feb-2004 | | | |
| Title of Invention: | Defect inspection apparatus and defect inspection method | | | |
| First Named Inventor/Applicant Name: | Takashi Yoneyama | | | |
| Filer: | Leonard Holtz/Nalini Sahadeo | | | |
| Attorney Docket Number: | 04083/LH | | | |
| Filed as Large Entity | | | | |
| Utility Filing Fees | | | | |
| Description | Fee Code | Quantity | Amount | Sub-Total in USD(\$) |
| Basic Filing: | | | | |
| Pages: | | | | |
| Claims: | | | | |
| Miscellaneous-Filing: | | | | |
| Petition: | | | | |
| Patent-Appeals-and-Interference: | | | | |
| Post-Allowance-and-Post-Issuance: | | | | |
| Extension-of-Time: | | | | |
| Extension - 2 months with \$0 paid | 1252 | 1 | 460 | 460 |

| Description | Fee Code | Quantity | Amount | Sub-Total in USD(\$) |
|-------------------|----------|----------|--------|----------------------|
| Miscellaneous: | | | | |
| Total in USD (\$) | | | | 460 |